

Boston University
Department of Electrical and Computer Engineering
SC505 STOCHASTIC PROCESSES
Exam 2 Summary

1. **Linear Systems and Random Processes:** $Y(t) = \int h(t, \tau)X(\tau) d\tau$

- Complete characterization difficult \implies Use second order relationships
- General Relations between 2nd order statistics:
 - Mean: $m_Y(t) = \int_{-\infty}^{\infty} h(t, \tau)m_X(\tau) d\tau$
 - Cross-correlation: $R_{YX}(t, s) = \int_{-\infty}^{\infty} h(t, \tau)R_{XX}(\tau, s) d\tau$
 - Output-correlation: $R_{YY}(t, s) = \int_{-\infty}^{\infty} \int_{-\infty}^{\infty} h(t, \tau)R_{XX}(\tau, \sigma)h(s, \sigma) d\tau d\sigma$

2. **LTI Systems and Wide-Sense Stationary Processes:**

- If $h(t)$ LTI and $X(t)$ WSS $\implies X(t), Y(t)$ are JWSS
- LTI Time-domain Relations between 2nd order statistics:
 - Mean: $m_Y = m_X \int_{-\infty}^{\infty} h(\tau) d\tau = H(0)m_X$
 - Cross-correlation: $R_{YX}(t) = \int_{-\infty}^{\infty} h(-\tau)R_{XX}(t - \tau) d\tau = h(-t) * R_{XX}(t)$
 - Output-correlation: $R_{YY}(t) = h(t) * R_{XX}(t) * h(-t)$
- LTI Frequency-domain Relations:
 - Cross-PSD: $S_{YX}(j\omega) = H(-j\omega)S_{XX}(j\omega)$ or $S_{YX}(s) = H(-s)S_{XX}(s)$
 - Output-PSD: $S_{YY}(j\omega) = |H(j\omega)|^2 S_{XX}(j\omega)$ or $S_{YY}(s) = H(s)H(-s)S_{XX}(s)$
- Shaping Filter: LTI system $H(s)$ driven by white noise.
- Properties of PSD of $S_{YY}(s)$: Quadrantal Symmetry of poles and zeros.
- Spectral Factorization: Can always write $S_{YY}(s) = G(s)G(-s)$ with $G(s)$ stable and causal. Yields shaping filter for given $S_{YY}(s)$.

3. **DT Linear Models:**

- Autoregressive (AR). All pole model, IIR
 - $x(n) = \sum_{i=1}^P a_i x(n-i) + w(n)$, $R_{WW}(n) = \sigma^2 \delta(n)$
 - $R_{XX}(m) = \sum_{i=1}^P a_i R_{XX}(m-i) + \sigma^2 \delta(m)$
 - Yule-Walker Equations. Linear equations for coefficients a_i :

$$\begin{bmatrix} R_{XX}(1) \\ R_{XX}(2) \\ \vdots \\ R_{XX}(P) \end{bmatrix} = \begin{bmatrix} R_{XX}(0) & R_{XX}(1) & \cdots & R_{XX}(P-1) \\ R_{XX}(1) & R_{XX}(0) & & R_{XX}(P-2) \\ \vdots & & \ddots & \vdots \\ R_{XX}(P-1) & R_{XX}(P-2) & \cdots & R_{XX}(0) \end{bmatrix} \begin{bmatrix} a_1 \\ a_2 \\ \vdots \\ a_P \end{bmatrix}$$

- Moving Average (MA). All zero model, FIR

$$- x(n) = \sum_{k=1}^Q b_k w(n-k) + w(n), R_{WW}(n) = \sigma^2 \delta(n)$$

- Nonlinear equations for coefficients b_i :

$$R_{XX}(m) = \begin{cases} \sigma^2 \left(\sum_{k=m}^Q b_k b_{k-m} \right) = \sigma^2 b(m) * b(-m) & m \leq Q \\ 0 & m > Q \end{cases}$$

- Correlation function is finite for MA

- Autoregressive Moving Average (ARMA). Both poles and zeros

$$- x(n) = \sum_{i=1}^P a_i x(n-i) + \sum_{k=1}^Q b_k w(n-k) + w(n), R_{WW}(n) = \sigma^2 \delta(n)$$

- In general, equations for coefficients a_i, b_k are nonlinear:

$$R_{XX}(m) = \sum_{i=1}^P a_i R_{XX}(m-i) + \sum_{j=0}^Q b_j R_{XW}(m-j), \quad b_0 = 1$$

- For $m > Q$: $R_{XX}(m) = \sum_{i=1}^P R_{XX}(m-i)$.

- Solution approach:

- (a) Solve linear equations for $m > Q$ for AR coefficients

- (b) Solve NL equations for MA coefficients: $S_{XX}(z)A(z)A(z^{-1}) = B(z)B(z^{-1})\sigma^2$

4. Sampling of Random Processes:

- Stochastic Nyquist Criterion Exists

- Result: If $S_{XX}(\omega) = 0$ for $|\omega| > W$ (i.e. is bandlimited) and $T_s < \pi/W$ then:

$$\lim_{N \rightarrow \infty} \left[2T_s \frac{W}{2\pi} \sum_{n=-N}^N X(nT_s) \frac{\sin W(t - nT_s)}{W(t - nT_s)} \right] \stackrel{mss}{=} X(t)$$

- Result: If $S_{XX}(\omega) = 0$ for $|\omega| > W$ and $T_s < \pi/W$ then:

$$\lim_{N \rightarrow \infty} 2T_s \frac{W}{2\pi} \sum_{n=-N}^N R_{XX}(nT_s) \frac{\sin W(\tau - nT_s)}{W(\tau - nT_s)} = R_{XX}(\tau)$$

5. Detection/Hypothesis Testing:

- Deterministic Decision Rule: Mapping of Observation space onto H_0, H_1 .

- Bayes Risk Approach:

- Priors $P_i = \Pr(H_i)$

- Observation Model: $P(y|H_i)$

- Costs: C_{ij} = Cost of deciding H_i when H_j true.

- Choose decision rule to min $E(\text{cost})$

- Likelihood Ratio Test (LRT) minimizes $E(\text{cost})$:

$$\mathcal{L}(y) = \frac{P_{Y|H_1}(y|H_1)}{P_{Y|H_0}(y|H_0)} \underset{H_0}{\overset{H_1}{\geq}} \frac{(C_{10} - C_{00})P_0}{(C_{01} - C_{11})P_1} = \eta$$

– Special Cases:

* MPE: $C_{ij} = 1 - \delta_{ij} \implies \underline{\text{MAP decision rule}}$

$$P_{H_1|Y}(H_1|y) \underset{H_0}{\overset{H_1}{\geq}} P_{H_0|Y}(H_0|y)$$

* MPE and $P_0 = P_1 = 1/2 \implies \underline{\text{ML decision rule}}$

$$P_{Y|H_1}(y|H_1) \underset{H_0}{\overset{H_1}{\geq}} P_{Y|H_0}(y|H_0)$$

* Gaussian Problems

– Randomized Tests: Given Two LRTs (LRT₁ and LRT₂) use LRT₁ with probability p and LRT₂ with probability $1 - p$. Has performance on line connecting two P_D, P_F pairs.

• Discrete Random Variables – know how to handle

• Sufficient Statistic: Function of the data that contains all information needed for test

• Performance:

$$E[\text{Cost}] = \underbrace{C_{00}P_0 + C_{01}P_1}_{\text{Fixed Cost}} + \underbrace{(C_{10} - C_{00})P_0P_F + (C_{11} - C_{01})P_1P_D}_{\text{Fn of threshold } \eta}$$

$$\text{Pr(error)} = \text{Pr[choose } H_0, H_1 \text{ true]} + \text{Pr[choose } H_1, H_0 \text{ true]} = (1 - P_D)P_1 + P_FP_0$$

– Both only depend on:

$$P_D = \text{Pr(Choose } H_1|H_1) = \int_{\{y|\text{say } H_1\}} P(y|H_1) dy = \int_{\mathcal{L} > \eta} P(\mathcal{L}|H_1) d\mathcal{L}$$

$$P_F = \text{Pr(Choose } H_1|H_0) = \int_{\{y|\text{say } H_1\}} P(y|H_0) dy = \int_{\mathcal{L} > \eta} P(\mathcal{L}|H_0) d\mathcal{L}$$

– Receiver Operating Characteristic: (ROC): Plot of P_D vs P_F as threshold is varied.

* Know properties – Concave, etc

* Discrete random variables: ROC consists of points

* Role of randomized tests

• Minimax Tests: Minimize the maximum $E[\text{Cost}]$ as P_1 is varied. Minimax test satisfies $P_D = \left(\frac{C_{01} - C_{00}}{C_{01} - C_{11}} \right) - \left(\frac{C_{10} - C_{00}}{C_{01} - C_{11}} \right) P_F$

• Neyman-Pearson Tests: Maximize P_D subject to $P_F \leq \alpha$. Solution is a LRT for some threshold

• M-ary Bayes Hypothesis Tests:

– Solution is:

$$\text{Choose } H_k \text{ if } \sum_{j=0}^{M-1} C_{kj}P(H_j|y) \leq \sum_{j=0}^{M-1} C_{ij}P(H_j|y) \quad \forall i$$

– Generates set of $M(M-1)/2$ unique comparisons defining decision regions:

$$\sum_{j=0}^{M-1} C_{kj}P_jP_{Y|H_j}(y|H_j) \underset{\text{Not } H_i}{\overset{\text{Not } H_k}} \geq \sum_{j=0}^{M-1} C_{ij}P_jP_{Y|H_j}(y|H_j) \quad \forall i, k \text{ pairs}$$

- Define $L_j(y) = \frac{P_{Y|H_j}(y|H_j)}{P_{Y|H_0}(y|H_0)}$, then test is:

$$\sum_{j=0}^{M-1} C_{kj} P_j L_j(y) \underset{\text{Not } H_i}{\overset{\text{Not } H_k}} \geq \sum_{j=0}^{M-1} C_{ij} P_j L_j(y) \quad \forall i, k \text{ pairs}$$

Linear Decision Boundaries in L_i space

- Special Cases:

- * MPE Cost Assignment $C_{ij} = 1 - \delta_{ij} \implies$ MAP decision rule:

$$\text{Choose } H_k \text{ if } P(H_k|y) \geq P(H_i|y) \quad \forall i$$

- * MPE and $P_i = 1/M \implies$ ML decision rule:

$$\text{Choose } H_k \text{ if } P(y|H_k) \geq P(y|H_i) \quad \forall i$$

- * Minimum Distance Classifier

- $P_{Y|H_K}(\underline{y}|H_k) = N(\underline{y}; \underline{m}_k, I)$
- ML Rule, $P_k = 1/M$
- \implies Minimum Distance Classifier

$$\text{Choose } H_k \text{ if } \|\underline{y} - \underline{m}_k\|^2 \leq \|\underline{y} - \underline{m}_i\|^2 \quad \forall i$$

6. Series Expansions, KLE, and Detection of Continuous Time Processes:

- Series expansions of stochastic processes: $X(t) = \sum_{i=1}^{\infty} X_i \phi_i(t)$
- KLE:
 - Find good basis functions for stochastic processes
 - Want uncorrelated coefficients: $E[X_i X_j] = \lambda \delta_{ij}$
 - Basis given by solutions to KL equation:

$$\int_{T_0}^{T_1} R_{XX}(t, \tau) \phi_m(\tau) d\tau = \lambda_m \phi_m(t)$$

- Eigendecomposition of $R_{XX}(t, \tau)$
- Gives optimal approximation of $X(t)$.
- White Noise: Every complete orthonormal basis (CON) is a KL basis
- Detection of CT waveforms
 - 1 Known signal in white noise:

$$\begin{aligned} H_0 : & \quad y(t) = w(t), \quad R_{WW}(\tau) = \sigma^2 \delta(\tau) \\ H_1 : & \quad y(t) = s(t) + w(t) \end{aligned}$$

- * Choose $\phi_1(t) = s(t)/\sqrt{E}$ and remaining ϕ_i to form CON set
- * y_1 is a sufficient statistic for problem
- * Matched Filter: $y_1 = \int y(s)s(t) dt \underset{H_0}{\overset{H_1}} \geq \gamma$
- * Performance depends on signal energy, not structure.

- 2 Known signals in white noise:

$$\begin{aligned} H_0 : \quad y(t) &= s_0(t) + w(t), & R_{WW}(\tau) &= \delta(\tau) \\ H_1 : \quad y(t) &= s_1(t) + w(t) \end{aligned}$$

* Approach 1) Let $y'(t) = y(t) - s_0(t)$ and apply previous results

* Approach 2) Let subset of basis functions span signal subspace

- M Known signals in white noise:

$$\begin{aligned} H_0 : \quad y(t) &= s_0(t) + w(t), & R_{WW}(\tau) &= \delta(\tau) \\ H_1 : \quad y(t) &= s_1(t) + w(t) \\ H_2 : \quad y(t) &= s_2(t) + w(t) \\ &\vdots \\ H_M : \quad y(t) &= s_M(t) + w(t) \end{aligned}$$

* Project onto signal subspace. Choose $\phi_1(t), \dots, \phi_{M+1}(t)$ to span the space of the signals.

$$\begin{array}{lll} H_0 : & \begin{array}{l} y_1 = s_{01} + w_1 \\ y_2 = s_{02} + w_2 \\ \vdots \\ y_M = s_{0M} + w_M \\ y_{M+1} = w_{M+1} \\ \vdots \end{array} & \begin{array}{l} H_1 : \quad \begin{array}{l} y_1 = s_{11} + w_1 \\ y_2 = s_{12} + w_2 \\ \vdots \\ y_M = s_{1M} + w_M \\ y_{M+1} = w_{M+1} \\ \vdots \end{array} \\ \dots \\ H_M : \quad \begin{array}{l} y_1 = s_{M1} + w_1 \\ y_2 = s_{M2} + w_2 \\ \vdots \\ y_M = s_{MM} + w_M \\ y_{M+1} = w_{M+1} \\ \vdots \end{array} \end{array} \end{array}$$

- Known signals in correlated noise:

$$\begin{aligned} H_0 : \quad y(t) &= s_0(t) + w(t), & R_{WW}(\tau) &\neq \delta(\tau) \\ H_1 : \quad y(t) &= s_1(t) + w(t) \end{aligned}$$

* Choose $\phi_i(t)$ via KLE of noise $w(t)$. w_i uncorrelated, but need all coefficients in general.

$$\begin{array}{ll} H_0 : & \begin{array}{l} y_1 = w_1 \\ y_2 = w_2 \\ y_3 = w_3 \\ \vdots \end{array} & H_1 : \quad \begin{array}{l} y_1 = s_1 + w_1 \\ y_2 = s_2 + w_2 \\ y_3 = s_3 + w_3 \\ \vdots \end{array} \end{array}$$

* In practice, truncate after some number of terms

7. Advice:

- Have basic results at your fingertips
- Know the assumptions/conditions behind formulas that you use!
- Perform sanity checks on answers – go back to basics if totally stuck (i.e. defining equation of expectation, variance etc)